

<b>Notice of References Cited</b>	Application/Control No. 10/796,963	Applicant(s)/Patent Under Reexamination ARAI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0115883	06-2004	Iwata et al.	438/257
	B	US-2004/0108512	06-2004	Iwata et al.	257/100
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002-252290	09-2002	Japan	Iwata et al.	
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	P					
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	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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